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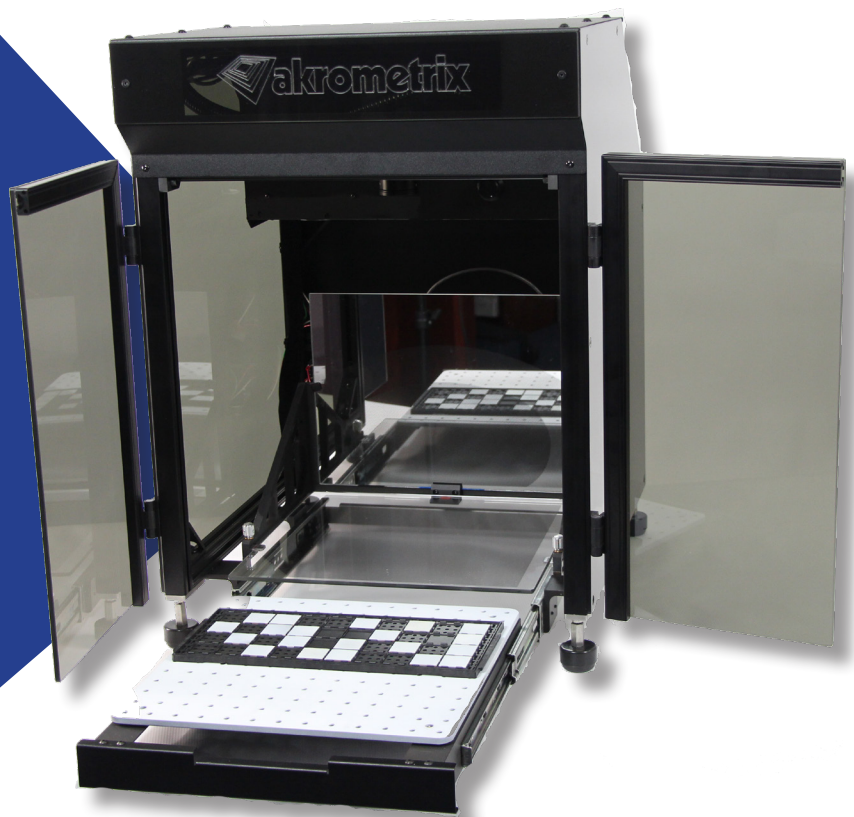
Thermal Warpage & Strain Metrology

TTSM

Lab Warpage System

Table Top Shadow Moiré w/ Manual loader and See-Thru Doors

- **“For lower volume R&D lab and Production Applications”**
- **Quick, Cost-Effective** R&D Warpage solution for Components and PCBs
- **Vision Technology:** Akrometrix Shadow Moiré
- **Runs on the Akrometrix Studio Software Suite**
- **Lightweight and mobile** for multiple labs



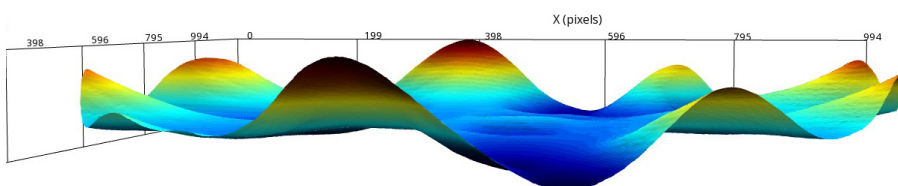
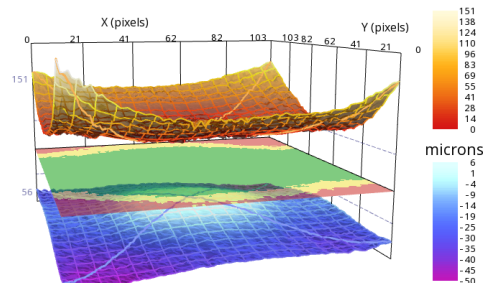
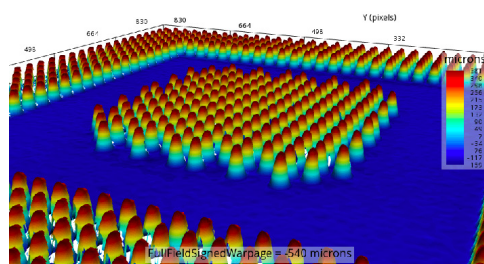
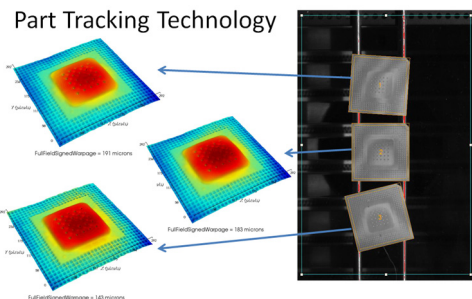
ON VIRTUALLY ANY SUBSTRATE:

Components

PCBs — Panels — Wafers

Individual Die — Wafers on Film Frame — Stacked Die

Part Tracking Technology



akrometrix.com
sales@akrometrix.com
1-404-486-0880

TTSM Technical Specifications

	TTSM with 100 LPI Grating	TTSM with 200 LPI Grating
Measurement Technology	Shadow Moiré	
Maximum Field of View (mm)	310x300	
Minimum Field of view (mm)	310x300	206x154
Maximum Sample Size (mm)	330x330	
Minimum Sample Size (mm)	6x6	4x4
Maximum Measured Surface Coplanarity	4000 microns	1000 microns
Resolution, Z-axis (vertical displacement)	2.5 microns	1.25 microns
Accuracy, Z-axis (vertical displacement)	2.5 microns / 2%	1.25 microns / 2%
Maximum Measurement Points per Acquisition	2,009,736	
Maximum Measurement Density (points per mm ²)	16	64
Minimum Measurement Density (points per mm ²)	16	
Automated Data Collection?	yes	
Batch Data Analysis?	yes	
Software	Akrometrix Studio 8.2 or Later	
Data Export Formats	.dat, .txt, .png	
Sample Load/ Unload Time	10 seconds, Manuel Load and Positioning	
Data Acquisition (Measurement) Time, approx.	2 seconds	
Data Analysis Time per Acquisition, approx.	2 seconds	
Approximate Depth, Width, Height (mm)	531 x 490 x 678	
Approximate Weight (kg)	32 kg	
Electrical requirements	110 VAC, 10A or 230VAC, 10A, 50Hz	
Other Utilities	N/A	

